


<b>Search Notes</b>  	<b>Application/Control No.</b>  10550017	<b>Applicant(s)/Patent Under Reexamination</b>  IKENAGA ET AL.
	<b>Examiner</b>  Caixia Lu	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
526	160, 165, 348.6, 943	6/2/08	/CL/

SEARCH NOTES		
Search Notes	Date	Examiner
Updated	5/26/08	/CL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
526	160, 165, 348.6, 943	5/26/08	/CL/